FAIRCHILD

SEMICONDUCTOR®

FDMC8296 N-Channel Power Trench[®] MOSFET 30V, 18A, 8.0m Ω

Features

- Max $r_{DS(on)} = 8.0 m\Omega$ at $V_{GS} = 10V$, $I_D = 12A$
- Max $r_{DS(on)}$ = 13.0m Ω at V_{GS} = 4.5V, I_D = 10A
- High performance trench technology for extremely low r_{DS(on)}
- Termination is Lead-free and RoHS Compliant



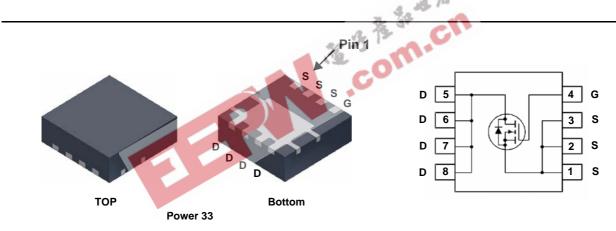
March 2008

General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench[®] process that has been especially tailored to minimize the on-state resistance. This device is welll suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

Application

- High side in DC DC Buck Converters
- Notebook battery power management
- Load switch in Notebook



MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V _{DS}	Drain to Source Voltage			30	V	
V _{GS}	Gate to Source Voltage			±20	V	
	Drain Current -Continuous (Package limited)	T _C = 25°C		18		
1	-Continuous (Silicon limited) $T_{C} = 25^{\circ}C$			44	^	
D	-Continuous	$T_A = 25^{\circ}C$	(Note 1a)	12	Α	
	-Pulsed			52		
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	60	mJ	
P _D	Power Dissipation	T _C = 25°C		27	W	
	Power Dissipation	$T_A = 25^{\circ}C$	(Note 1a)	2.3	VV	
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C	

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	4.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1	a) 53	C/W

Package Marking and Ordering Information

ſ	Device Marking	Device	Package	Reel Size	Tape Width	Quantity
	FDMC8296	FDMC8296	Power 33	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_{D} = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu$ A, referenced to 25°C		17		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24V,$ $V_{GS} = 0V,$ $T_{J} = 125^{\circ}C$			1 250	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA
On Chara	cteristics					
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.0	1.9	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu$ A, referenced to 25°C	-	-6		mV/°C
	Static Drain to Source On Resistance	V _{GS} = 10V, I _D = 12A		6.5	8.0	
r _{DS(on)}		$V_{GS} = 4.5V, I_D = 10A$		9.5	13.0	mΩ
		$V_{GS} = 10V, I_D = 12A, T_J = 125^{\circ}C$		9.0	12.8	
9 _{FS}	Forward Transconductance	$V_{DD} = 5V, I_D = 12A$		44		S
Dynamic	Characteristics		-			
C _{iss}	Input Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ f = 1MHz		1038	1385	pF
C _{oss}	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$		513	685	pF
C _{rss}	Reverse Transfer Capacitance			87	135	pF
Rg	Gate Resistance	f = 1MHz		0.9		Ω
	Characteristics	C C C				
t _{d(on)}	Turn-On Delay Time			9	18	ns
t _r	Rise Time	V _{DD} = 15V, I _D = 12A,		3	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 6\Omega$		19	35	ns
t _f	Fall Time			2	10	ns
-		$V_{GS} = 0V$ to 10V		16	23	nC
Q _{g(TOT)}	Total Gate Charge	$V_{GS} = 0V \text{ to } 4.5V$ $V_{DD} = 15V,$		7.6	10.6	nC
Q _{gs}	Total Gate Charge	I _D = 12A		3		nC
Q _{qd}	Gate to Drain "Miller" Charge			2.5		nC
Drain-Sou	urce Diode Characteristics			·]		
		V _{GS} = 0V, I _S = 12A (Note 2)		0.82	1.3	
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 1.9A$ (Note 2)		0.73	1.2	V
t _{rr}	Reverse Recovery Time			25	45	ns
Q _{rr}	Reverse Recovery Charge	$I_{F} = 12A, di/dt = 100A/\mu s$		9	18	nC

NOTES:

1. $R_{0,L}$ is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{0,LC}$ is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 53°C/W when mounted on a 1 in² pad of 2 oz copper



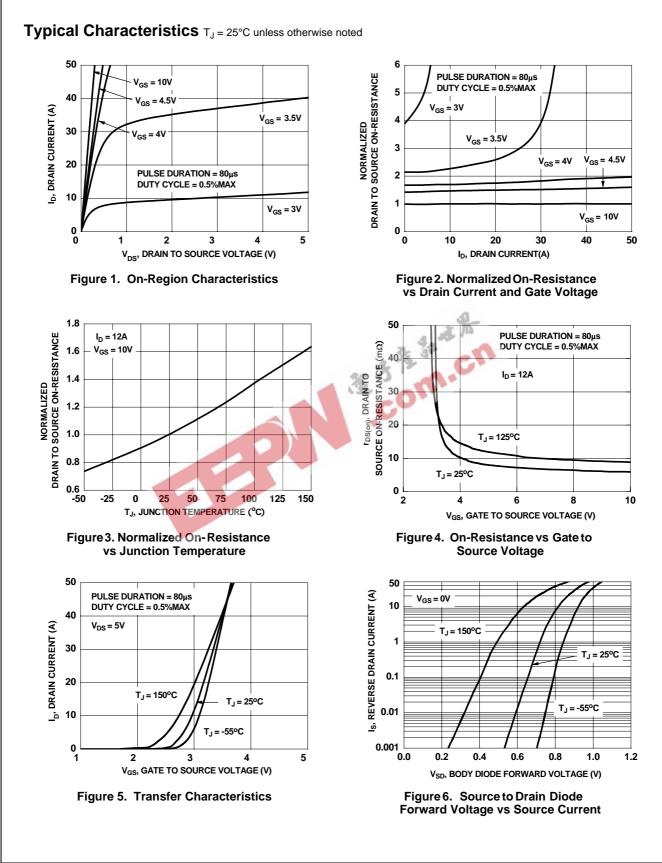
b. 125°C/W when mounted on a minimum pad of 2 oz copper



2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.

3. Starting $T_J = 25^{\circ}C$; N-ch: L = 1 mH, $I_{AS} = 11A$, $V_{DD} = 27V$, $V_{GS} = 10V$.

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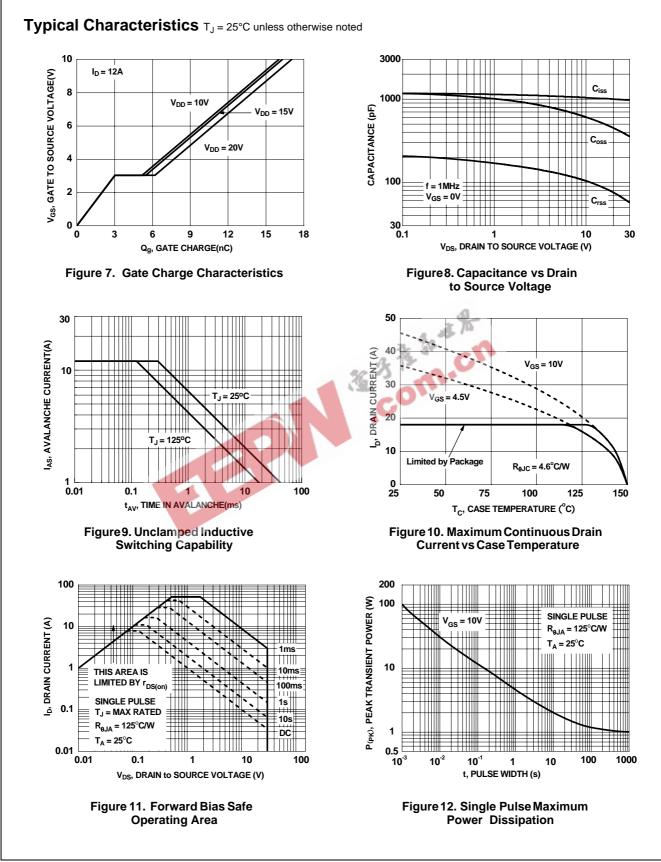


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FDMC8296 Rev.B

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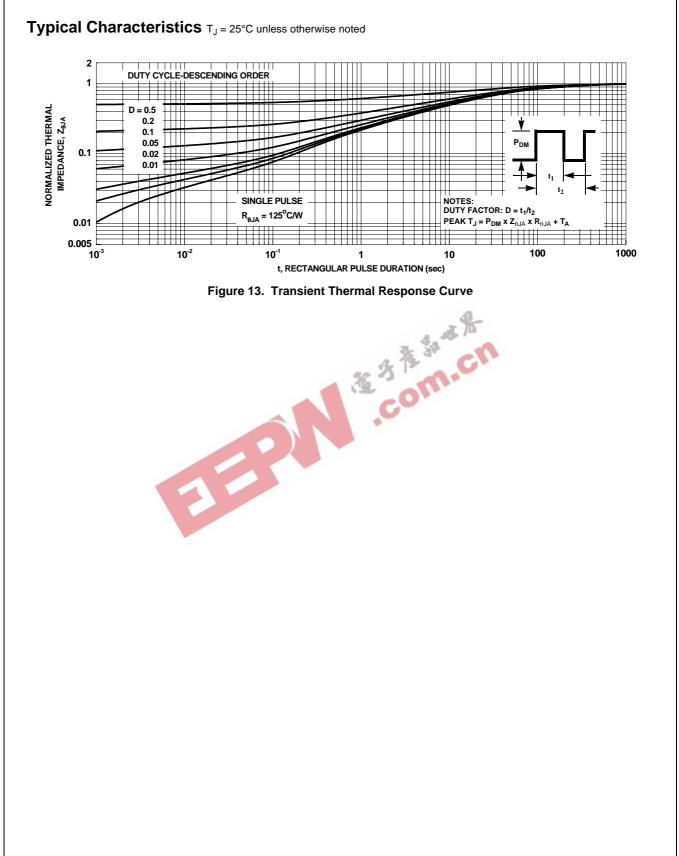
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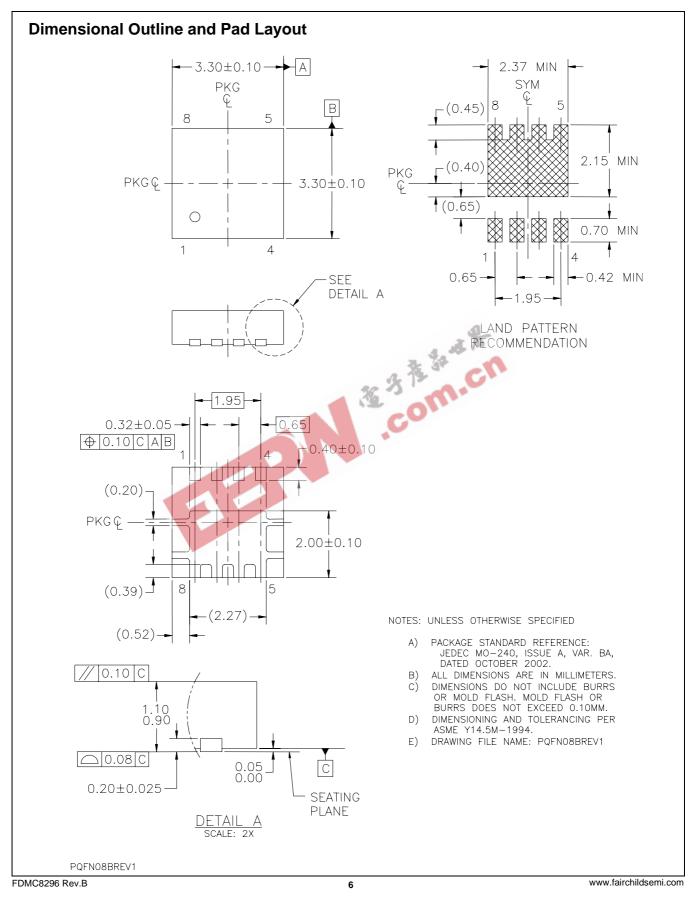
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